

DapuStor X2900P 400GB SSD Test Results



The Third Party Test Results for the DapuStor R5100D are based on a comprehensive evaluation to ensure compatibility, performance, and reliability performed by the Open Composable Compatibility Lab (OCCL). The assessment covers basic interoperability and specialized workload performance using industry-standard benchmarking tools. This test result is not an endorsement of the third-party product by Western Digital and no warranty of the product is expressed or implied by Western Digital or the OCCL.

For more information related OCCL, see: <https://www.opencomposable.com/>.

Drive Details

Drive	DapuStor X2900P 400GB
Form Factor	U.2 15mm
Interface	PCIe® Gen4, NVMe™ 1.4a
Security	N/A
Power	14W (Active)
Power Idle	6W
Part Number	DPXD3101TOS100T4000

The following table displays the status and results of the testing of a specific device. The four columns represent specific configurations which progressively increase in terms of complexity in the following order: Local benchmark x1 > Data24-4200 x1 > Data24-4200 x8 > Data24-4200 x24. All devices will start with the Local x1 and Data24-4200 x1. Poor performance or interoperability issues in any configuration can eliminate the device from further consideration. The individual tests are consistent with general industry practices and reporting. Western Digital's OpenFlex™ Data24 NVMe-oF™ Storage Platform extends the high performance of NVMe flash to shared storage. The storage platform provides low-latency sharing of NVMe SSDs over a high-performance Ethernet fabric to deliver similar performance to locally attached NVMe SSDs.

For additional information on Western Digital's OpenFlex Data24 NVMe-oF Storage Platform, see:

<https://www.westerndigital.com/products/data-center-platforms/openflex-data24-nvme-of-platform?sku=1ES2380>.

DapuStor X2900P 400GB Top Line Performance

Test Description	Local x1	Data24-4200 x1	Data24-4200 x8	Data24-4200 x24
Read Bandwidth (128KB) MB/s	7,042	7,160	41,488	~124,464
Write Bandwidth (128KB) MB/s	6,794	6,496	36,048	~108,144
Random Read (4KB)K IOPS	1,680	1,710	8,956	~26,867
Random Write (4KB) K IOPS	1,305	1,305	8,621	~25,863
Random Mixed (4KB) K IOPS	1,624	1,618	8,978	~26,935
4K Random Write Latency (µs)	6	16	19	~19
4K Random Read Latency (µs)	19	26	29	~29
4K Random Write 4-9s µs	121	23	24	~24
4K Random Read 4-9s µs	144	32	34	~34

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The Normalized Test Results Table show the scalability from one to 24 devices using the Local x1 configuration as the baseline. With perfect linearity, the 8-device test would provide 8X the performance of the one device test and the 24-device test would provide 24X performance. For these charts, the baseline is always the Local x1 configuration therefore the value of the Local x1 configuration is set to 1.00X.

- IF = 1.00X: The same performance as the baseline.
- IF > 1.00X: Faster / Better performance than the baseline.
 - Example: 2.00X is twice as fast as the baseline.
- IF < 1.00X: Slower / Worse performance than the baseline.
 - Example: if the Normalized performance is 0.50X, then it is only one-half as fast as the Baseline.

The following table displays tests 2-4 normalized to test 1 (Local x1), the percentages in tests 2-4 should generally increase with more complex and larger configurations. The two QoS values (4-9s) by their stochastic behavior can have significant variability.

DapuStor X2900P 400GB Normalized to Local x1 Top Line Performance

Test Description	Local x1	Data24-4200 x1	Data24-4200 x8	Data24-4200 x24
Read Bandwidth (128KB) MB/s	1.000X	1.017X	5.892X	~17.676X
Write Bandwidth (128KB) MB/s	1.000X	0.956X	5.306X	~15.917X
Random Read (4KB) K IOPS	1.000X	1.018X	5.331X	~15.993X
Random Write (4KB) K IOPS	1.000X	1.000X	6.607X	~19.820X
Random Mixed (4KB) K IOPS	1.000X	0.996X	5.528X	~16.583X
4K Random Write Latency (μs)	1.000X	2.856X	3.347X	~3.347X
4K Random Read Latency (μs)	1.000X	1.372X	1.487X	~1.487X
4K Random Write 4-9s μs	1.000X	0.192X	0.197X	~0.197X
4K Random Read 4-9s μs	1.000X	0.224X	0.235X	~0.235X

Coefficients of Variation (CoV) are a standard statistical measure that are directly comparable to other CoVs as opposed to Standard Deviations (SD) that can only be compared if the mean is the same for two sets of data. $CoV = SD/MEAN$. NAND storage has a higher variability than DRAM, for example, that is highly consistent. NAND is a noise technology that has higher error rates than most solid state memory. Each manufacturing process has its own baseline error rate. These error rates are based on one second intervals provided by standard monitoring tools like iostat.

DapuStor X2900P 400GB CoV Analysis

Test Description	Local x1	Data24-4200 x1	Data24-4200 x8	Data24-4200 x24
Read Bandwidth (128KB) MB/s	0.000%	0.000%	1.183%	~1.183%
Write Bandwidth (128KB) MB/s	0.008%	0.002%	1.841%	~1.841%
Random Read (4KB) K IOPS	0.001%	0.000%	0.161%	~0.161%
Random Write (4KB) K IOPS	0.009%	0.008%	0.280%	~0.280%
Random Mixed (4KB) K IOPS	0.010%	0.007%	0.013%	~0.013%
4K Random Write Latency (μs)	0.774%	1.481%	0.332%	~0.332%
4K Random Read Latency (μs)	0.272%	2.981%	0.102%	~0.102%
4K Random Write 4-9s μs	0.689%	1.871%	0.506%	~0.506%
4K Random Read 4-9s μs	0.000%	2.795%	0.712%	~0.712%

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Exceedance Chart

The following charts contain the technical and most accurate information. Exceedance charts are typically used for only single drive, single process, queue depth one analysis as in the following example. The chart is the most fundamental measurement of SSD or disk performance as it shows the minimum latency as well as the expected error rate and latency for the device under test. These results are often referred to as the "number of nines". For example, "4-9s" shows the latency or response time for 9999 of 10000 IOs. The number of IOs grows exponentially with the increase in the number of nines. This chart shows for 6-9s that the best performer for random writes is the small blue dotted line at approximately 90 μ s. Random writes are faster than random reads, because random writes are cached in the asynchronous write buffer and are periodically written to the underlying NAND media. Exceedance charts can be run and compared as long as all tests were run on similar systems using the same workload.

Latency Exceedance for DapuStor X2900P 400GB

